

Notice of References Cited	Application/Control No. 10/588,355	Applicant(s)/Patent Under Reexamination ONO, KOTARO	
	Examiner KIP T. KOTTER	Art Unit 3617	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	The Language of Physics - Dictionary and Research Guide, "Second moment of area", http://www.123exp-science.com/t/01554506012/			
	V				
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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